**AMENDMENTS TO THE CLAIMS** 

The following listing of claims will replace all prior versions, and listings, of

claims in the application:

**Listing of Claims:** 

Claim 1 (currently amended): A semiconductor device module structure

comprising:

a high-resistance layer of a first conductive type;

a base layer of a second conductive type formed in an upper part of

the high-resistance layer of the first conductive type;

an emitter region of a first conductive type formed in an upper part of

the base layer of the second conductive type;

an emitter electrode connected to the emitter region;

an insulated gate electrode adjacent to the base layer of the second

conductive type;

a guard ring part-where diffusion, wherein a portion of the guard ring

has been made deep around a cell region including the emitter region has been

made deep;

a passivation layer formed on the an upper part of the guard ring part

and not extending onto thean upper part of the cell region;

a buffer layer of a first conductive type formed on an underside of the

high-resistance layer of the first conductive type;

Page 2 of 7

Application No.: 10/597136 Amendment Dated: February 12, 2008 Reply to Office action of: December 14, 2007

a collector layer of the second conductive type formed on the <u>an</u> underside of a-the buffer layer of the first conductive type;

a collector electrode connected to the collector layer; and
a metal flat plate upper heat-sinking part connected to the emitter
electrode at a height such that it is non-contacting with the passivation film.

Claim 2 (currently amended): The semiconductor device module structure of claim 1, characterized in that the module structure of awherein the semiconductor device module structure further comprises a diode part, and wherein a cathode electrode at located in an upper part of the diode part between the high-resistance layer and the upper heat-sinking part are is connected to the upper heat-sinking part.

Claim 3 (new): The semiconductor device module structure of claim 1, wherein one end of the metal flat plate upper heat-sinking part is connected to the emitter electrode and the opposite end of the metal flat plate heat-sinking part is connected to a substrate.